

Search Notes

Application/Control No.

10/696,105

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

MONTHIE ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	8	2/3/2006	JSL
716	9	2/3/2006	JSL
716	17	2/3/2006	JSL
716	18	2/3/2006	JSL
716	11	2/3/2006	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	8,9	2/3/2006	JSL
716	11	2/3/2006	JSL
716	17,18	2/3/2006	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB]	2/3/2006	JSL